

LIST OF PATENTS AND PUBLICATIONS										Attorney Docket:		Serial No.	
APPLICANT'S INFORMATION										101215-75		09/998,446	
DISCLOSURE STATEMENT (Form PTO-1449 Modified)										Applicant:			
										Jörg-Thomas Zettler et al.			
										Filing Date:		Group:	
										Nov. 30, 2001		TBA	
U.S. PATENT DOCUMENTS													
Examiner's Initial	Document Number	Date	Name	Class	Sub Class	Filing Date If appropriate							
ML	AA	5 4 0 3 4 3 3	4/1995	P. Morrison, et al.	156	626							
	AB												
	AC												
	AD												
	AE												
	AF												
	AG												
	AH												
	AI												
	AJ												
	AK												
FOREIGN PATENT DOCUMENTS													
	Document Number	Date	Country	Class	Sub Class	Translation Yes No							
ML	AL	44 19 476	12/1994	Germany				✓					
	AM												
	AN												
	AO												
	AP												
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)													
ML	AR	Y. Li, et al. Simultaneous in situ Measurement of Substrate Temperature and Layer Thickness Using Diffuse Reflectance Spectroscopy (DRS) During Molecular Beam Epitaxy" Journal of Crystal Growth 175/176 (1997) pgs. 250-255											
	AS	K.Knorr, et al. "Real-time Monitoring of P-based Semiconductor Growth by Linear-optical Spectroscopy" Eighth International Conference on Indium Phosphide and Related Materials, 1996, IPRM '96, pgs. 590-593											
	AT												
EXAMINER:										DATE CONSIDERED: Apr. 17, 2003			
<ul style="list-style-type: none"> • EXAMINER: Initial if Reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered, include copy of this form with next communication to applicant. • 													